



Shenzhen Tuofeng Semiconductor Technology Co., Ltd

**P -CHANNEL ENHANCEMENT MODE POWER MOSFET****TF120P06K****• General Description**

The TF120P06K combines advanced trench MOSFET technology with a low resistance package to provide extremely low  $R_{DS(on)}$ . This device is ideal for load switch and battery protection applications.

**• Features**

Advance high cell density Trench technology

Low  $R_{DS(on)}$  to minimize conductive loss

Low Gate Charge for fast switching

Low Thermal resistance

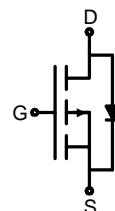
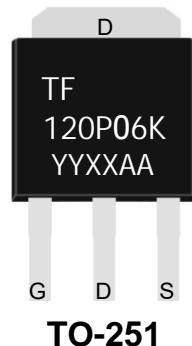
**• Application**

MB/VGA Vcore

SMPS 2<sup>nd</sup> Synchronous Rectifier

POL application

BLDC Motor driver

**• Product Summary** $V_{DS} = -60V \quad I_D = -80A$  $R_{DS(on)(-10V typ)} = 11.5m\Omega$  $R_{DS(on)(-4.5V typ)} = 14.0m\Omega$ **TO-251****TO-252****• Ordering Information:**

Part NO.	TF120P06K		
Marking 1	120P06K:TF120P06K		
Marking 2	TF:tuofeng; YY:year code; XX:Week; AA:device code;		
MOQ	TO-251:50/PCS TO-252:2500/PCS		

**• Absolute Maximum Ratings ( $T_C = 25^\circ C$ )**

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	$V_{DS}$	-60	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current	$I_D @ T_C = 25^\circ C$	-80	A
	$I_D @ T_C = 75^\circ C$	-56	A
	$I_D @ T_C = 100^\circ C$	-48	A
Pulsed Drain Current <sup>①</sup>	$I_{DM}$	-300	A
Total Power Dissipation	$P_D @ T_C = 25^\circ C$	115	W
Total Power Dissipation	$P_D @ T_A = 25^\circ C$	2.0	W
Operating Junction Temperature	$T_J$	-55 to 150	°C
Storage Temperature	$T_{STG}$	-55 to 150	°C

Note: ① Pulse Test : Pulse width  $\leq 300\mu s$ , Duty cycle  $\leq 2\%$  ;



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Single Pulse Avalanche Energy	E <sub>AS</sub>	480	mJ
Avalanche Current	I <sub>AS</sub> I <sub>AR</sub>	-25	A

**•Thermal resistance**

Parameter	Symbol	Min.	Typ.	Max.	Unit
Thermal resistance, junction - case	R <sub>thJC</sub>	-	-	5.0	° C/W
Thermal resistance, junction - ambient	R <sub>thJA</sub>	-	-	55	° C/W
Soldering temperature, wave soldering for 8s	T <sub>sold</sub>	-	-	265	° C

**•Electronic Characteristics**

Parameter	Symbol	Condition	Min.	Typ	Max.	Unit
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =250uA	-60			V
Gate Threshold Voltage	V <sub>GS(TH)</sub>	V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =250uA	-1.1	-1.8	-2.5	V
Drain-Source Leakage Current	I <sub>DSS</sub>	V <sub>DS</sub> =-60V, V <sub>GS</sub> =0V			-1.0	uA
Gate- Source Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =±20V ,V <sub>DS</sub> =0V			±100	nA
Static Drain-source On Resistance	R <sub>DS(ON)</sub>	V <sub>GS</sub> =-10V, I <sub>D</sub> =-20A		11.5	15.0	mΩ
		V <sub>GS</sub> =-4.5V, I <sub>D</sub> =-20A		14.0	18.0	mΩ
Forward Transconductance	g <sub>FS</sub>	V <sub>DS</sub> =-20V, I <sub>D</sub> =-20A		32		S
Source-drain voltage	V <sub>SD</sub>	I <sub>S</sub> =-20A			1.20	V

**•Electronic Characteristics**

Parameter	Symbol	Condition	Min.	Typ	Max.	Unit
Input capacitance	C <sub>iss</sub>	V <sub>ds</sub> =-20V, V <sub>gs</sub> =0V f = 1MHz	-	8700	-	pF
Output capacitance	C <sub>oss</sub>		-	290	-	
Reverse transfer capacitance	C <sub>rss</sub>		-	210	-	

**•Gate Charge characteristics(T<sub>a</sub> = 25°C)**

Parameter	Symbol	Condition	Min.	Typ	Max.	Unit
Gate Resistance	R <sub>g</sub>	f = 1MHz		2.1		Ω
Total gate charge	Q <sub>g</sub>	V <sub>DD</sub> = -30V I <sub>D</sub> = -20A V <sub>GS</sub> = -10V	-	140	-	nC
Gate - Source charge	Q <sub>gs</sub>		-	19.0	-	
Gate - Drain charge	Q <sub>gd</sub>		-	28.0	-	
Turn-ON Delay time	t <sub>D(on)</sub>	V <sub>GS</sub> =-10V ,V <sub>DS</sub> =-30V R <sub>G</sub> =1.0Ω, I=-20A		26		ns
Turn-ON Rise time	t <sub>r</sub>			21		ns
Turn-Off Delay time	t <sub>D(off)</sub>			138		ns
Turn-Off Fall time	t <sub>f</sub>			30		ns

## Typical Performance Characteristics

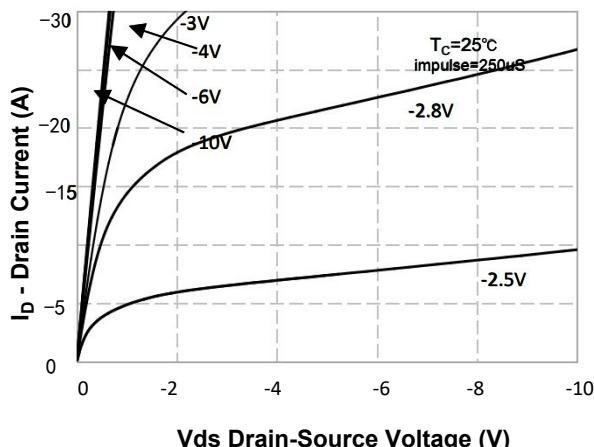


Figure 1. On-Region Characteristics

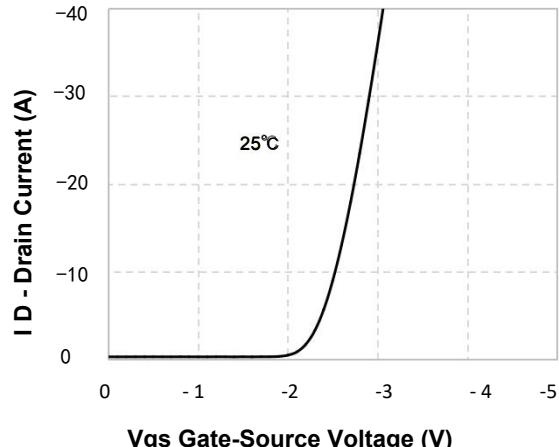


Figure 2. Transfer Characteristics

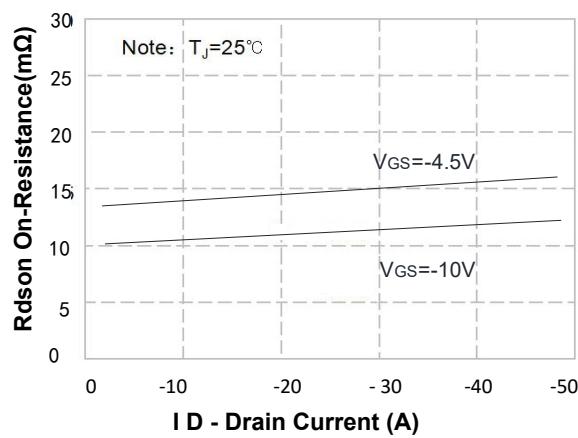


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

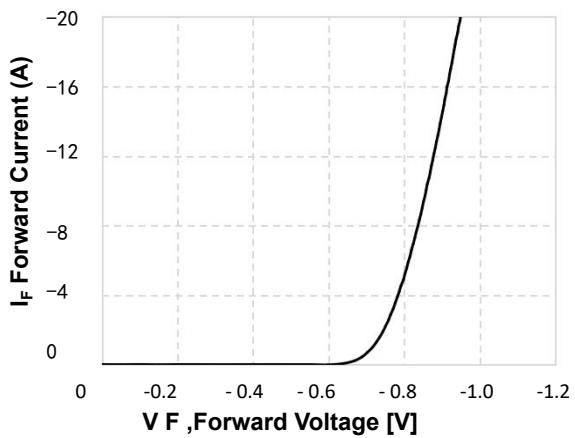


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

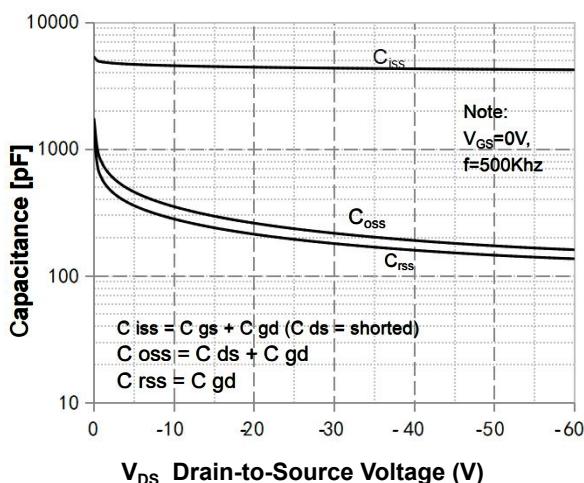


Figure 5. Capacitance Characteristics

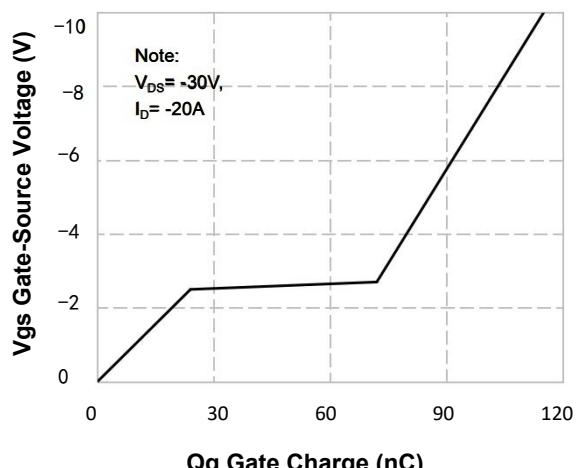


Figure 6. Gate Charge Characteristics

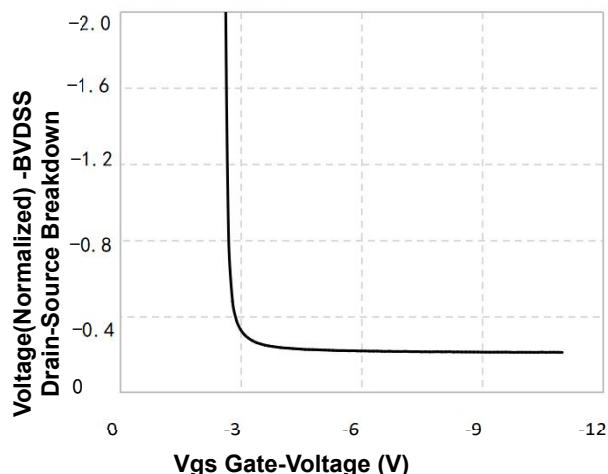


Figure 7. Breakdown Voltage Variation  
vs Gate-Voltage

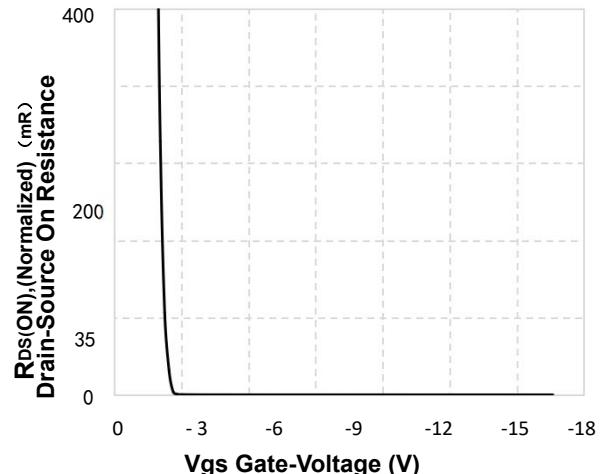


Figure 8. On-Resistance Variation  
vs Gate Voltage

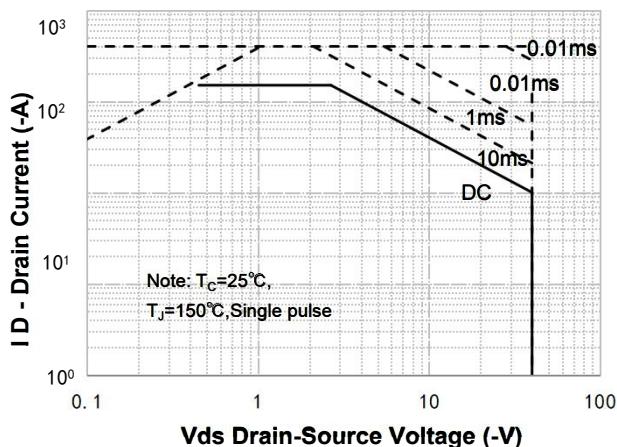


Figure 9. Maximum Safe Operating Area

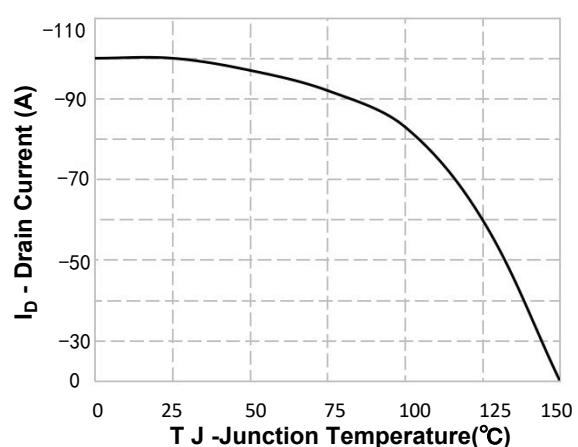


Figure 10. Maximum Continuous Drain Current vs Case Temperature

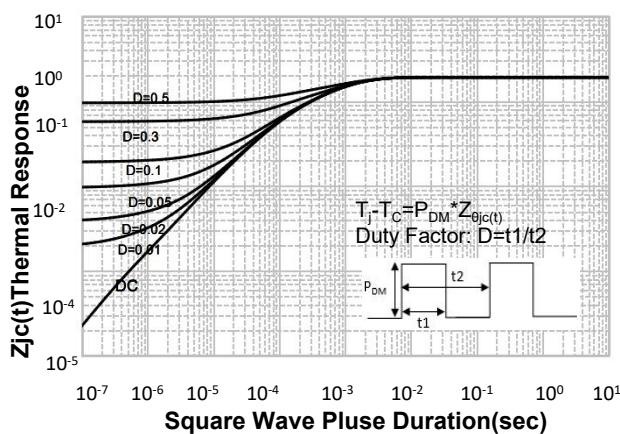
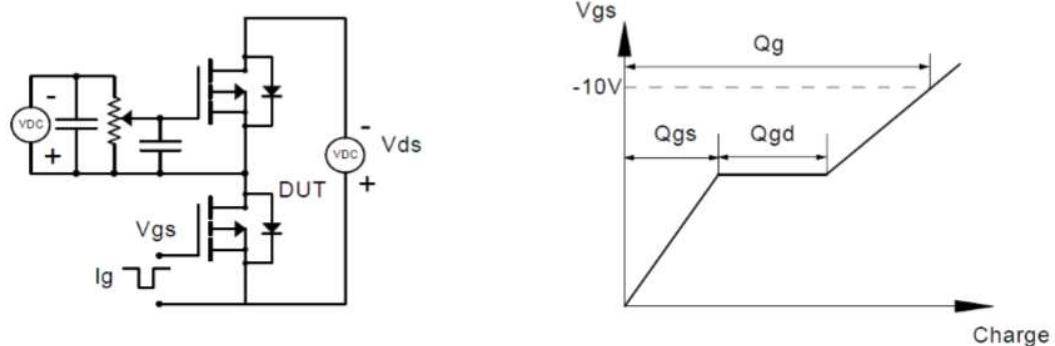


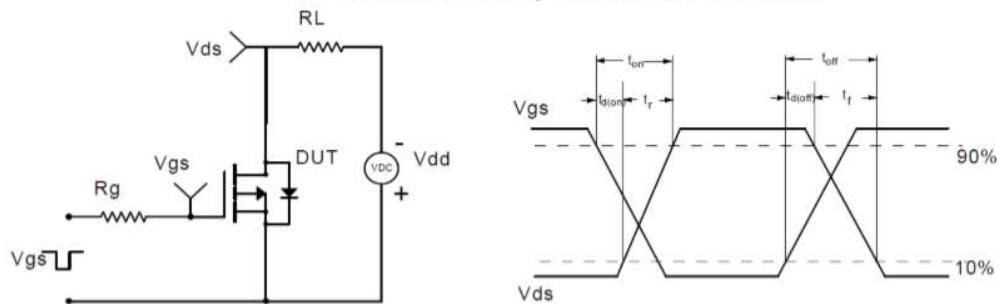
Figure 11. Transient Thermal Response Curve

## Test Circuit

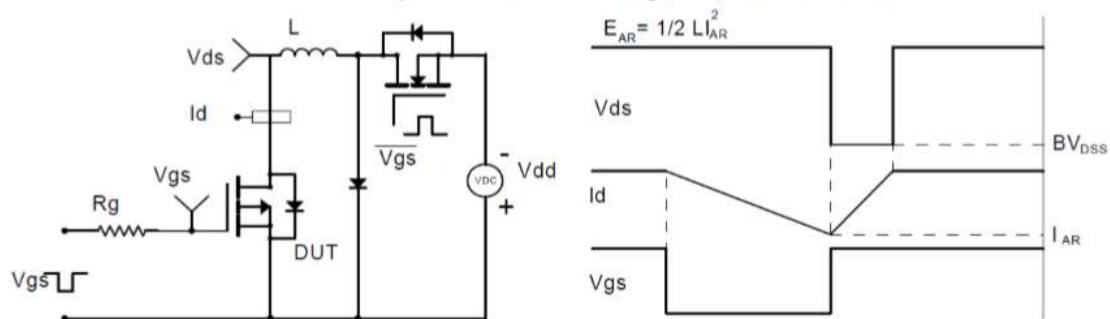
Gate Charge Test Circuit & Waveform



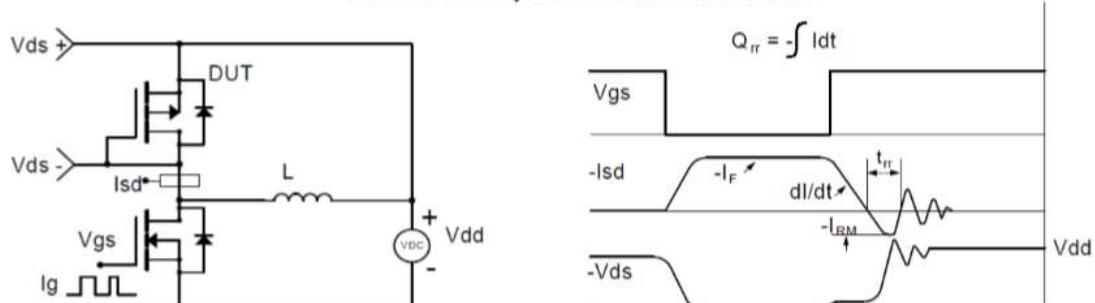
Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms





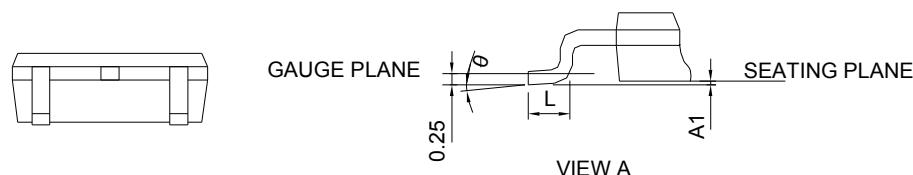
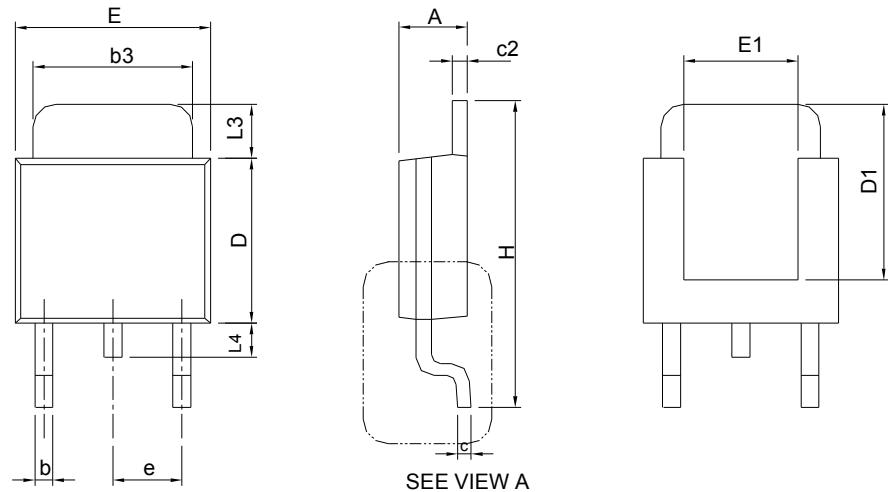
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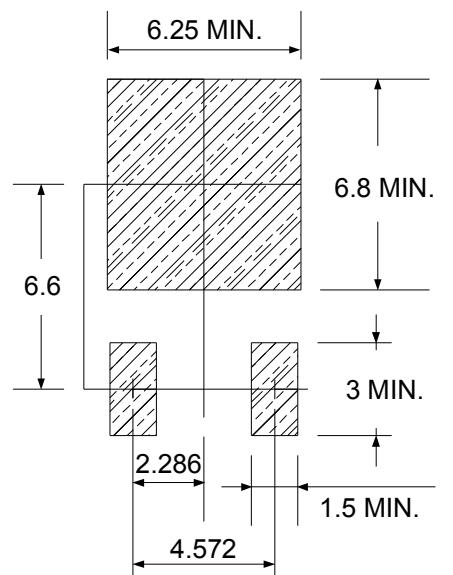
## Package Information

TO-252



SYMBOL	TO-252			
	MILLIMETERS		INCHES	
	MIN.	MAX.	MIN.	MAX.
A	2.18	2.39	0.086	0.094
A1		0.13		0.005
b	0.50	0.89	0.020	0.035
b3	4.95	5.46	0.195	0.215
c	0.46	0.61	0.018	0.024
c2	0.46	0.89	0.018	0.035
D	5.33	6.22	0.210	0.245
D1	4.57	6.00	0.180	0.236
E	6.35	6.73	0.250	0.265
E1	3.81	6.00	0.150	0.236
e	2.29 BSC		0.090 BSC	
H	9.40	10.41	0.370	0.410
L	0.90	1.78	0.035	0.070
L3	0.89	2.03	0.035	0.080
L4		1.02		0.040
θ	0°	8°	0°	8°

### RECOMMENDED LAND PATTERN



UNIT: mm